



ISO
#

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **YAMAGISHI, Yasuo, et al.**

Group Art Unit: **2829**

Serial No.: **10/621,445**

Examiner: **HOLLINGTON, Jermele M.**

Filed: **July 18, 2003**

P.T.O. Confirmation No.: 1112

For. **PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD THEREOF**

PETITION FOR EXTENSION OF TIME

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Date: May 10, 2005

Sir:

Applicants petition the Commissioner for Patents to extend the time for response to the Office Action dated January 10, 2005 for one month, from April 10, 2005 to May 10, 2005.

Attached please find a check in the amount of \$120.00 to cover the cost of the extension for a large entity. In the event that any additional fees are due in connection with this paper, please charge our Deposit Account No. 01-2340.

Respectfully submitted,

**ARMSTRONG, KRATZ, QUINTOS,
HANSON & BROOKS, LLP**

William L. Brooks
Attorney for Applicant
Reg. No. 34,129

05/11/2005 HAL111 00000115 10621445

01 FC:1251

120.00 OP

WLB/nrp
Atty. Docket No. **030868**
Suite 1000
1725 K Street, N.W.
Washington, D.C. 20006
(202) 659-2930



23850

PATENT TRADEMARK OFFICE